

Resource Summary Report

Generated by SPARC SAWG on Aug 9, 2026

Nikon: XT H 225 ST uCT system

RRID:SCR_023687

Type: Tool

Proper Citation

Nikon: XT H 225 ST uCT system (RRID:SCR_023687)

Resource Information

URL: <https://industry.nikon.com/en-us/products/x-ray-ct/xt-h-225-xt-h-320/>

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Description: Provides insight into the inside of components and specimens, allowing users to visualize, analyze and measure complex internal geometry as well as surfaces, all non-destructively. Versatile microfocus CT system for high resolution inspection in R&D and failure analysis of components ranging from tiny plastic connectors up to aluminum castings.

Synonyms: Nikon XTH 225 ST microfocus Computer Tomography system

Resource Type: instrument resource

Keywords: USEDit, instrument, equipment, microfocus CT system, high resolution components inspection, components inspection,

Availability: Restricted

Resource Name: Nikon: XT H 225 ST uCT system

Resource ID: SCR_023687

Record Creation Time: 20230616T050221+0000

Record Last Update: 20260808T190257+0000

Ratings and Alerts

No rating or validation information has been found for Nikon: XT H 225 ST uCT system.

No alerts have been found for Nikon: XT H 225 ST uCT system.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We found 2 mentions in open access literature.

Listed below are recent publications. The full list is available at [SPARC SAWG](#) .

Straight PJ, et al. (2024) Mapping the avian visual tectofugal pathway using 3D reconstruction. The Journal of comparative neurology, 532(2), e25558.

Bernardes D, et al. (2017) Comprehensive catwalk gait analysis in a chronic model of multiple sclerosis subjected to treadmill exercise training. BMC neurology, 17(1), 160.